* Full list of publications:

1. "A study on structural, optical, electrical and microstructural properties of thin TiO_x films upon thermal oxidation: Effect of substrate temperature and oxidation temperature"
   Monjoy Sreemany, Ankita Bose, Suchitra Sen

   Physica B 405 (2010) 85-93.

2. "Influence of chemical composition, phase and thickness of TiO_x ($x \leq 2$) seed layer on the growth and orientation of the perovskite phase in sputtered PZT thin films"
   Monjoy Sreemany, Ankita Bose, Suchitra Sen

   Mater. Chem. Phys. 115 (2009) 453-462.

3. "Influence of calcinations ambient and film thickness on the optical and structural properties of sol-gel TiO_2 thin films"
   Monjoy Sreemany and Suchitra Sen
   Mater. Res. Bull. 42 (2007) 177-189.

4. "Effect of substrate temperature and annealing temperature on the structural, electrical and microstructural properties of thin Pt films by rf magnetron sputtering"
   Monjoy Sreemany and Suchitra Sen
   Appl. Surf. Sci. 253 (2006) 2739-2746.
5. "A simple spectrophotometric method for determination of the optical constants and band gap energy of multiple layer TiO_2 thin films"
   Monjoy Sreemany, Suchitra Sen
   Mater. Chem. Phys., 83 (2004) 169-177.

6. "Near surface composition of some alloys by X-ray photoelectron spectroscopy"
   M. Sreemany and T. B. Ghosh
   Pramana – J. Phys., 57 (2001) 809 – 820.

7. "XPS studies on the oxidation behavior of SiC particles"
   M. Sreemany, T. B. Ghosh, B. C. Pai and M. Chakraborty
   Matterials Research Bulletin, 33 (1998) 189 -198.

8. "Application of Rachinger's method to separate overlapped doublets in X-ray photoelectron spectrum"
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9. "Interface properties of thin oxide grown on strained $Si_{1-x}Ge_x$ layer at low temperature"
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10. "Angle resolved XPS studies of inhomogeneous specimens of polycrystalline silver covered with uniform graphite overlayers"

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11. "On the XPS peak shape analysis"
M. Sreemany and T. B. Ghosh
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12. "On the selection of an integration limit for quantitative XPS analysis"
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13. "On the carbon 1s photoelectron spectrum of cellulose"
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14. "Characterization of white-rotted and brown-rotted rice straw by X-ray photoelectron spectroscopy"
S. Dey, T. K. Maiti, M. Sreemany, T. B. Ghosh and B. C. Bhattacharya
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